

OpenView 太赫兹摄像头

Scientific metrology camera fitted to the UV, visible, Infrared and Terahertz spectral domain $(0.1 \mu m \dot{a} > 3000 \mu m)$

OpenView is a new device based on the extension of microbolometric infrared camera dedicated to measurement and analysis of monochromatic optical beam and large spectral band from UV to Terahertz waves.

NeTHIS offers a cost-efficient and versatile device suited forbeam analysis and metrology of wide



ranges of commercial and laboratory Infrared, Terahertz and sub-Terahertz sources.

Key Benefits:

High spectral agility (0,1 -> 3000µm) covering the UV, visible, SWIR, MWIR, LWIR and terahertz domains







The largest detection surface area > 60x60mm

Compact uncooled Infrared technology

Dedicated to a large diversity of coherent and non coherent sources:

Solid-states Lasers

Fiber Lasers

Quantum Cascade Lasers (QCL)

Molecular Lasers (Excimers, CO2, ...)

Diodes and electronic terahertz and microwave oscillators (Gunn, BWO, ...)

Free electron lasers, black-body radiation

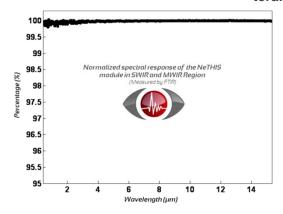
Suited for High-power lasers sources

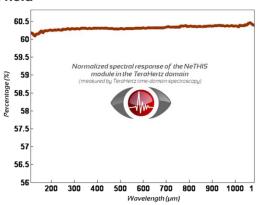




Figures

OpenView offers the largest spectral sensitivity homogeneity from the infrared to the terahertz field





Technical specifications

Typical Parameters of OpenView		
Product size	90*90*200mm ³	
Working Temperature	Room temperature	
Supply voltage	Sector voltage	
Plug-in	IEEEI394/Ethernet	
Sensitive detection area	70*70mm ²	
Pixel size	100µm	
Soectral range	0.1-3000μm	
Damage threshold	>1W/cm ²	
Minimum messurable signal	<1nW/pixel	

Applications

Metrology and laser beam analysis (laboratories, R&D centers, industries)

2D and 3D beam metrology and analysis

Optimization and sources alignment (continuous or pulsed)

Multispectral sources characterization





TeraCam 太赫兹相机

Multispectral camera (IR et TeraHertz) of wide field 2D and 3D imaging system

TeraCam is a high performance camera design not

only for laser beam metrology but also for 2D and 3D imaging and Non Destructive Testing of insulating materials(composites, foams, plastics, ceramics...)

NeTHIS offers a versatile and cost-efficient solution formultispectral imaging, dedicated to the largest commercial and laboratory sources in the Infrared, Terahertz and/or MMW electromagnetic domain.



The TeraCam relies on a multispectral module (SWIR, LWIR, MWIR, FIR, THz) implemented on a cooled or uncooled Infrared cores

Key Benefits:

High spectral agility (0,1 -> 3000µm) covering UV, visible, SWIR, MWIR, LWIR and terahertz domains



- -Terahertz 2D imaging on optical domains > 60x60mm
- -Terahertz tomography of insulating materials
- -Dedicated to a large diversity of coherent and noncoherent sources:

Solid-states Lasers

Fiber Lasers

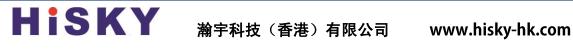
Quantum Cascade Lasers (QCL)

Molecular Lasers (Excimers, CO2, ...)

Diodes and electronic terahertz and micro-microwave oscillators (Gunn, BWO, ...)

Free electron lasers, black-body radiation

-Suited for High-power lasers sources





Technical specifications:

Parameters	OpenView	TeraCAM	
Product size	60*60*300mm ³	200*200*300mm ³	
Working Temperature	Room temperature Uncooled IR Detector		
Supply voltage	Sector voltage		
Plug-in	IEEEI394/Ethernet		
Sensitive detection field	700*700mm ²		
Pixel size	200 µ m	100 µ m	
Number of Pixels	700*700		
Spatial resolution	Millimetre(Diffraction limited)		
Spectral range	0.1-3000 µ m		
Minimum measurable signal	<50µW/cm² per pixel		
Acquisition rate	1-10Hz	1-50Hz	

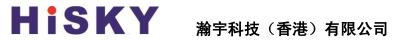
Applications:

Multispectral imaging applied to R&D and industrial applications

- Physical and optical characterization of insulating materials (density, fatigue, humidity, heat diffusion, strain...)
- Millimeter wave global inspection through opaque insulating materials (delamination, crack, mould, materiel inhomogeneity)
- **ODE 2D** and 3D penetrating imaging of welding, gluing and attached systems

New applications possibilities for laboratories and industries

- 2D and 3D optical beams imaging and analysis
- TeraHertz and MMW source optimization and alignment (continuous or pulsed)
- TeraHertz Tomography
- Multispectral source metrology



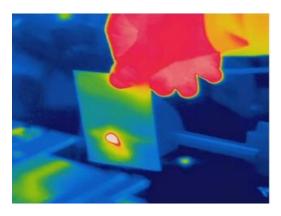


TeraCard 太赫兹显示卡

-Universal Laser beam viewer card The widest broadband accesible from 0.1 to 3000µm

TeraCard

The Broadband laser viewer card offers a hand-held or post-mounted operation for beam viewing, alignment and metrology using an innovative large-size sensitive conversion cards. Increase your lasers operation in complete **safety**using the detection sensitivity of the Teracard pack.



Coupled with the smallest, lightest and most affordable thermal imaging camera, laser manipulation benefits for the widest spectral electromagnetic bandwidth from UV, visible and infrared up to Terahertz and microwave radiations

Key Benefits:

High spectral agility (0,1 -> 3000µm) covering UV, visible, SWIR, MWIR, LWIR and terahertz domains

Large detection surface area > 40x40mm

Dedicated to a large diversity of coherent and non coherent sources:

Solid-states Lasers

Fiber Lasers

Quantum Cascade Lasers (QCL)

Molecular Lasers (Excimers, CO2, ...)

Diodes and electronic terahertz and micro-microwave

oscillators (Gunn, BWO, ...)

Free electron lasers, black-body radiation

Suited for High-power lasers sources

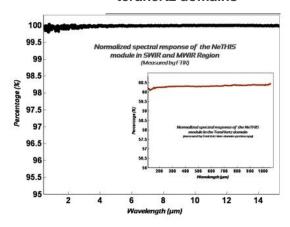






Figures

TeraCard offers the largest homogeneity of spectral sensitivity from the infrared to the terahertz domains



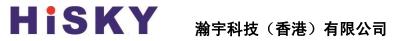
Technical specifications

Parameters	TeraCARD	
Size	89*54mm Custsom size available	
Detection surface diameter	25.4mm 50.8mm	
Spectralband	0.1-3000µm From UV to THz	
Sensitivity	<100 µ W/cm ²	
Damage threshold	>W/cm ²	

Applications

A large aplication field for safety lasers manipulation

- Lasers beam optimization and alignment for industry and scientific metrology
- Personnal laser safety in working zone
- **Components and Lasers system inspections**
- Thermal imaging (lasers, rooms, ...)
- Infrared and visible fluorescence
- **Black-body radiations characterization**
- **Multispectral source metrology**





TeraPOWER 太赫兹功率计

TeraHertz broadband auto-calibrated Powermeter

Product overview

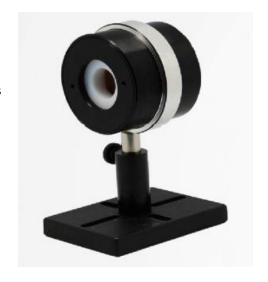
TeraPOWER is implemented as an sensitive auto-calibrated flux-meter extending the Infrared and thermal technology up to TeraHertz and sub-Terahertz electromagnetic domain. It combines a high sensitivity detection level on a broad spectral bandwidth with the largest detector surface.

TeraPOWER offers a cost-efficient and versatile device suited for a wide range of commercial and laboratory Infrared, TeraPOWER and sub-Terahertz sources.

Auto-calibrated flux-meter extending the infrared and thermal technology up to TeraHertz and sub-Terahertz electromagnetic domain

Key benefits

- Absolute auto-calibrated power-meter
- Large detector area
- Broadband IR and THz beam metrology
- Suited to a large variety of IR ,THz and MMW sources
- Electronic diodes(Gunn,IMPATT,TUNNETT)
- **BWO**
- QCIs lasers
- Molecular lasers
- Free Electron Laser
- Cost-efficient and easy to use

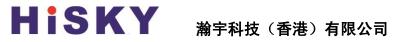


NeTHIS opens a new area for a wide range of THz metrology and applications

Laboratory and industrial THz and Sub-THz applications

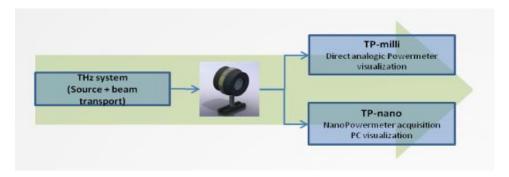
- -Scientific metrology and industrial R&D
- -CW and pulsed soured charcterisation and optimisation
- -optical characterisation of industrial materials
- -active imaging and tomography for non-destructive testing

TeraHertz broadband auto-calibrated Powermeter





Available acquisition modes



Typical specifications @0.1THz

Parameters	TeraPOWER TP-Milli	TeraPOWER TP-Nano	
Product size	60*60*70mm ³		
Working Temperature	Room temperature		
Supply voltage	None		
Plug-in	BNC/RS232	BNC/RS232/GPIB	
Sensitive detection field	1-25mm of Diameter(on demand)		
Data acquisition mode	Multimeter analogical PC acquisition	Nano Voltmeter PC acquisition	
Spectral range	0.1-30THz(10µm-3mm)	0.1-30THz(10µm-3mm)	
Minimum measurable signal	<100 µ W	<1 µ W	
Sensitivity	0.1V/W	1V/W	
Measurements errors	10 µ W	<0.1 µ W	





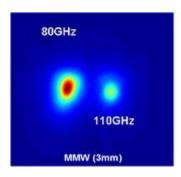
Applications:

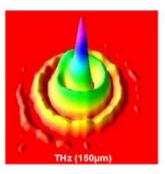
Scientific metrology

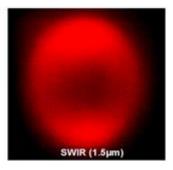
Beam metrology:

NeTHIS develops innovative tools allowing beam metrology on the largest spectral range, from the **UV to the MMW**. Our range scientific metrology product is suited to:

- Beam Analysis and Profiling
- Power measurment
- Spectral characterization
- Set up alignment and optimization







Our solutions dedicated to optical metrology:



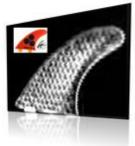
OpenView



Applications:

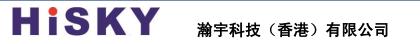
Non Destructive Testing:

NeTHIS technology widens its Infrared optical system to the field of Terahertz. "A sight inside the matter", opens a new way for volume inspection and Non destructive testing of industrial insulating materials.











NeTHIS solutions apply on advanced materials characterization from various fields such as aeronautics, building, automobile, chemistry, food-processing, wood, industries...





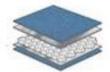
The application of NeTHIS technology for non destructive testing are :

- Millimetric internal default detection
- Inside structures inhomogeneity detection
- Physical property differences (density, pressure, temperature)
- Humidity control of materials

Our solutions dedicated to the Non Destructive Testing in volume:



TeraCam





Offres de services